



RF Power LDMOS Transistors

High Ruggedness N-Channel Enhancement-Mode Lateral MOSFETs

These RF power devices are designed for commercial applications operating at frequencies from 1200 to 1400 MHz such as commercial L-Band radars. The devices are suitable for use in pulse applications.

Typical Pulse Performance: In 1200–1400 MHz reference circuit, $V_{DD} = 50$ Vdc, $I_{DQ(A+B)} = 100$ mA, $P_{in} = 25$ W

| Frequency (MHz) | Signal Type | P_{out} (W) | G_{ps} (dB) | η_D (%) |
|-----------------|--|---------------|---------------|--------------|
| 1200 | Pulse (300 μ sec, 12% Duty Cycle) | 950 Peak | 15.8 | 46.5 |
| 1300 | | 1120 Peak | 16.5 | 47.5 |
| 1400 | | 1000 Peak | 16.1 | 46.6 |

Load Mismatch/Ruggedness

| Frequency (MHz) | Signal Type | VSWR | P_{in} (W) | Test Voltage | Result |
|-----------------|---|----------------------------------|----------------------------------|--------------|--------------------------|
| 1400 (1) | Pulse (128 μ sec, 10% Duty Cycle) | > 20:1 at All Phase Angles | 31.6 Peak (3 dB Overdrive) | 50 | No Device Degradation |

1. Measured in 1400 MHz narrowband production circuit.

Features

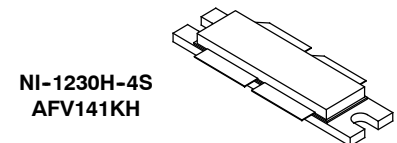
- Internally Input and Output Matched for Broadband Operation and Ease of Use
- Device Can Be Used in a Single-Ended, Push-Pull or Quadrature Configuration
- Qualified up to a Maximum of 50 V_{DD} Operation
- High Ruggedness, Handles > 20:1 VSWR
- Integrated ESD Protection with Greater Negative Voltage Range for Improved Class C Operation and Gate Voltage Pulsing
- Characterized with Series Equivalent Large-Signal Impedance Parameters

Typical Applications

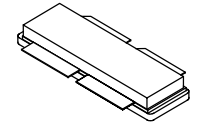
- Commercial L-Band Radar Systems

**AFV141KH
 AFV141KHS
 AFV141KGS**

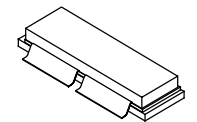
**1200–1400 MHz, 1000 W PEAK, 50 V
 AIRFAST RF POWER LDMOS
 TRANSISTORS**



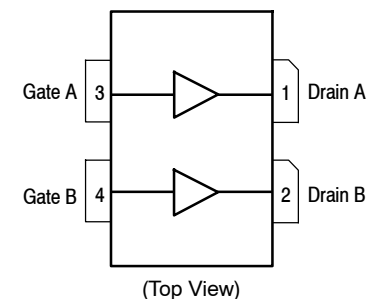
NI-1230H-4S
 AFV141KH



NI-1230S-4S
 AFV141KHS



NI-1230GS-4L
 AFV141KGS



Note: The backside of the package is the source terminal for the transistor.

Figure 1. Pin Connections



Table 1. Maximum Ratings

| Rating | Symbol | Value | Unit |
|--|-----------|-------------|-----------|
| Drain-Source Voltage | V_{DSS} | -0.5, +105 | Vdc |
| Gate-Source Voltage | V_{GS} | -6.0, +10 | Vdc |
| Storage Temperature Range | T_{stg} | -65 to +150 | °C |
| Case Operating Temperature Range | T_C | -40 to +150 | °C |
| Operating Junction Temperature Range (1,2) | T_J | -40 to +225 | °C |
| Total Device Dissipation @ $T_C = 25^\circ\text{C}$ Derate above 25°C | P_D | 910 4.55 | W W/°C |

Table 2. Thermal Characteristics

| Characteristic | Symbol | Value (2,3) | Unit |
|---|-----------------|-------------|------|
| Thermal Impedance, Junction to Case Case Temperature 60°C, 1000 W Peak, 128 μsec Pulse Width, 10% Duty Cycle, 50 Vdc, $I_{DQ(A+B)} = 100\text{ mA}$, 1400 MHz | $Z_{\theta JC}$ | 0.018 | °C/W |

Table 3. ESD Protection Characteristics

| Test Methodology | Class |
|---------------------------------------|-------------------|
| Human Body Model (per JESD22-A114) | 2, passes 2500 V |
| Machine Model (per EIA/JESD22-A115) | B, passes 200 V |
| Charge Device Model (per JESD22-C101) | IV, passes 2000 V |

Table 4. Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

| Characteristic | Symbol | Min | Typ | Max | Unit |
|----------------|--------|-----|-----|-----|------|
|----------------|--------|-----|-----|-----|------|

Off Characteristics (4)

| | | | | | |
|--|---------------|-----|---|----|-----------------|
| Gate-Source Leakage Current ($V_{GS} = 5\text{ Vdc}$, $V_{DS} = 0\text{ Vdc}$) | I_{GSS} | — | — | 1 | μAdc |
| Drain-Source Breakdown Voltage ($V_{GS} = 0\text{ Vdc}$, $I_D = 10\ \mu\text{Adc}$) | $V_{(BR)DSS}$ | 105 | — | — | Vdc |
| Zero Gate Voltage Drain Leakage Current ($V_{DS} = 50\text{ Vdc}$, $V_{GS} = 0\text{ Vdc}$) | I_{DSS} | — | — | 1 | μAdc |
| Zero Gate Voltage Drain Leakage Current ($V_{DS} = 105\text{ Vdc}$, $V_{GS} = 0\text{ Vdc}$) | I_{DSS} | — | — | 10 | μAdc |

On Characteristics

| | | | | | |
|---|--------------|------|------|------|-----|
| Gate Threshold Voltage (4) ($V_{DS} = 10\text{ Vdc}$, $I_D = 520\ \mu\text{Adc}$) | $V_{GS(th)}$ | 1.3 | 1.8 | 2.3 | Vdc |
| Gate Quiescent Voltage (5) ($V_{DD} = 50\text{ Vdc}$, $I_{DQ(A+B)} = 100\text{ mAdc}$, Measured in Functional Test) | $V_{GS(Q)}$ | 1.6 | 2.1 | 2.6 | Vdc |
| Drain-Source On-Voltage (4) ($V_{GS} = 10\text{ Vdc}$, $I_D = 2.6\text{ Adc}$) | $V_{DS(on)}$ | 0.05 | 0.16 | 0.35 | Vdc |

Dynamic Characteristics (5)

| | | | | | |
|---|-----------|---|------|---|----|
| Reverse Transfer Capacitance ($V_{DS} = 50\text{ Vdc} \pm 30\text{ mV(rms)ac}$ @ 1 MHz, $V_{GS} = 0\text{ Vdc}$) | C_{rss} | — | 2.98 | — | pF |
|---|-----------|---|------|---|----|

1. Continuous use at maximum temperature will affect MTTF.
2. MTTF calculator available at <http://www.nxp.com/RF/calculators>.
3. Refer to AN1955, *Thermal Measurement Methodology of RF Power Amplifiers*. Go to <http://www.nxp.com/RF> and search for AN1955.
4. Each side of device measured separately.
5. Measurement made with device in push-pull configuration.

(continued)

Table 4. Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted) (continued)

| Characteristic | Symbol | Min | Typ | Max | Unit |
|---|----------|------|------|------|------|
| Functional Tests ^(1,2) (In Freescale Narrowband Production Test Fixture, 50 ohm system) $V_{DD} = 50\text{ Vdc}$, $I_{DQ(A+B)} = 100\text{ mA}$, $P_{out} = 1000\text{ W Peak}$ (100 W Avg.), $f = 1400\text{ MHz}$, 128 μsec Pulse Width, 10% Duty Cycle | | | | | |
| Power Gain | G_{ps} | 16.0 | 17.7 | 19.5 | dB |
| Drain Efficiency | η_D | 46.0 | 52.1 | — | % |
| Input Return Loss | IRL | — | -18 | -9 | dB |

Load Mismatch/Ruggedness (In Freescale Narrowband Test Fixture, 50 ohm system) $I_{DQ(A+B)} = 100\text{ mA}$

| Frequency (MHz) | Signal Type | VSWR | P_{in} (W) | Test Voltage, V_{DD} | Result |
|-----------------|--|----------------------------|-------------------------------|------------------------|-----------------------|
| 1400 | Pulse (128 μsec , 10% Duty Cycle) | > 20:1 at all Phase Angles | 31.6 Peak (3 dB Overdrive) | 50 | No Device Degradation |

Table 5. Ordering Information

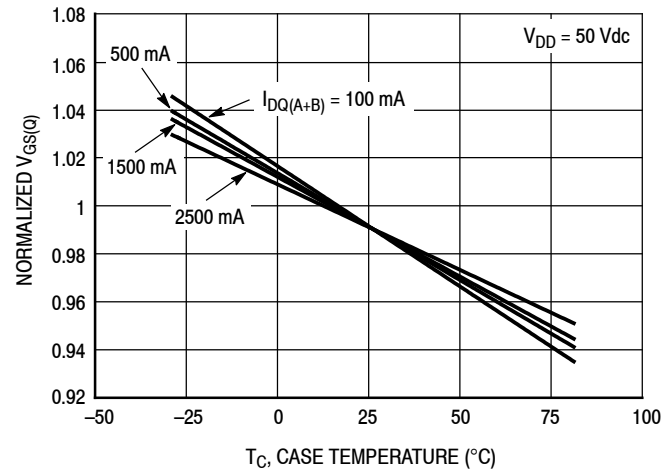
| Device | Tape and Reel Information | Package |
|-------------|--|-------------------------|
| AFV141KHR5 | R5 Suffix = 50 Units, 56 mm Tape Width, 13-inch Reel | NI-1230H-4S, Eared |
| AFV141KHSR5 | | NI-1230S-4S, Earless |
| AFV141KGSR5 | | NI-1230GS-4L, Gull Wing |

1. Measurement made with device in push-pull configuration.
2. Measurements made with device in straight lead configuration before any lead forming operation is applied. Lead forming is used for gull wing (GS) parts.

TYPICAL CHARACTERISTICS



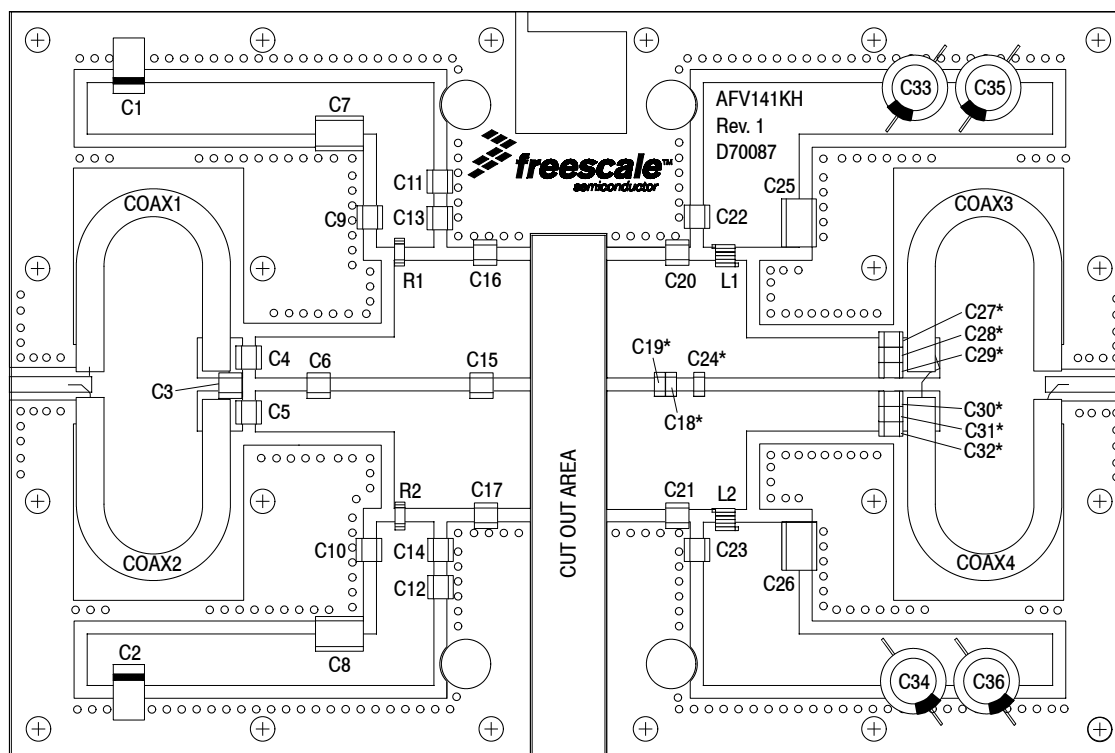
Note: Each side of device measured separately.
Figure 2. Capacitance versus Drain-Source Voltage



| I_{DQ} (mA) | Slope (mV/°C) |
|---------------|---------------|
| 100 | -2.06 |
| 500 | -1.96 |
| 1500 | -1.94 |
| 2500 | -1.72 |

Figure 3. Normalized V_{GS} versus Quiescent Current and Case Temperature

1400 MHz NARROWBAND PRODUCTION TEST FIXTURE — 4" x 6" (10.2 cm x 15.2 cm)



* C18, C19, C24, C27, C28, C29, C30, C31 and C32 are mounted vertically.

Figure 4. AFV141KH(HS) Narrowband Test Circuit Component Layout — 1400 MHz

Table 6. AFV141KH(HS) 1400 MHz Narrowband Circuit Component Designations and Values

| Part | Description | Part Number | Manufacturer |
|-------------------------------------|--|----------------------|---------------|
| C1, C2 | 22 μ F, 35 V Tantalum Capacitors | T491X226K035AT | Kemet |
| C3 | 2.7 pF Chip Capacitor | ATC100B2R7BT500XT | ATC |
| C4, C5, C9, C10, C13, C14, C22, C23 | 27 pF Chip Capacitors | ATC100B270JT500XT | ATC |
| C6 | 1.5 pF Chip Capacitor | ATC100B1R5BT500XT | ATC |
| C7, C8 | 2.2 μ F Chip Capacitors | C1825C225J5RACTU | Kemet |
| C11, C12 | 0.1 μ F Chip Capacitors | CDR33BX104AKY9S | AVX |
| C15 | 2.2 pF Chip Capacitor | ATC100B2R2BT500XT | ATC |
| C16, C17 | 0.7 pF Chip Capacitors | ATC100B0R7BT500XT | ATC |
| C18 | 1.5 pF Chip Capacitor | ATC100B1R5BT500XT | ATC |
| C19 | 1.2 pF Chip Capacitor | ATC100B1R2BT500XT | ATC |
| C20, C21 | 2.2 pF Chip Capacitors | ATC100B2R2BT500XT | ATC |
| C24 | 1.5 pF Chip Capacitor | ATC100B1R5BT500XT | ATC |
| C25, C26 | 0.01 μ F Chip Capacitors | C1825C103K1GACTU | Kemet |
| C27, C28, C29, C30, C31, C32 | 27 pF Chip Capacitors | ATC100B270JT500XT | ATC |
| C33, C34, C35, C36 | 470 μ F, 63 V Electrolytic Capacitors | MCGPR63V477M13X26-RH | Multicomp |
| Coax1, Coax2, Coax3, Coax4 | 35 Ω Semi Rigid Coax 1.454" Shield Length | HSF-141-35-C | Hongsen Cable |
| L1, L2 | 17.5 nH, 4 Turn Inductors | GA3095-ALC | Coilcraft |
| R1, R2 | 100 Ω , 1 W Chip Resistors | CRCW2512100RFKEG | Vishay |
| PCB | Arlon AD255A, 0.03", $\epsilon_r = 2.55$ | D70087 | MTL |

TYPICAL CHARACTERISTICS — 1400 MHz PRODUCTION TEST FIXTURE

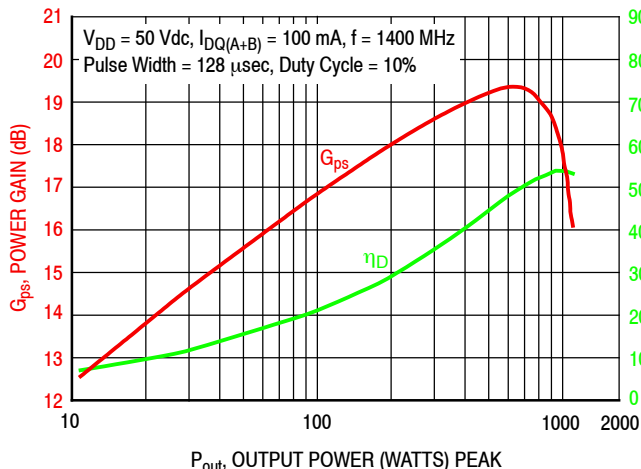
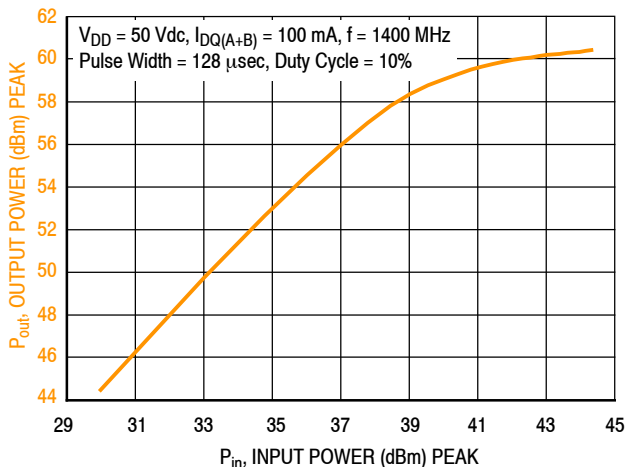


Figure 5. Power Gain and Drain Efficiency versus Output Power



| f (MHz) | P1dB (W) | P3dB (W) |
|---------|----------|----------|
| 1400 | 948 | 1079 |

Figure 6. Output Power versus Input Power

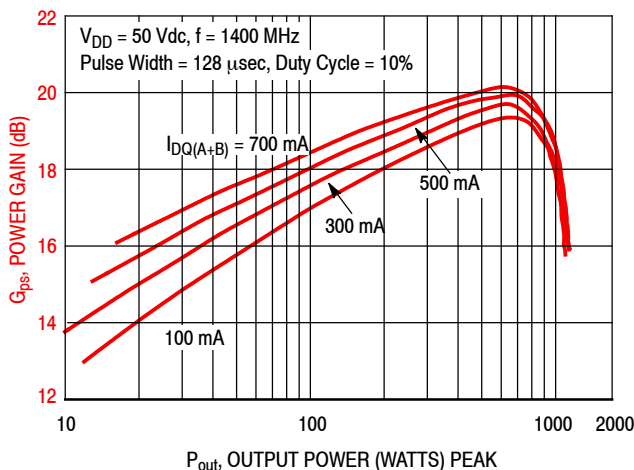


Figure 7. Power Gain versus Output Power

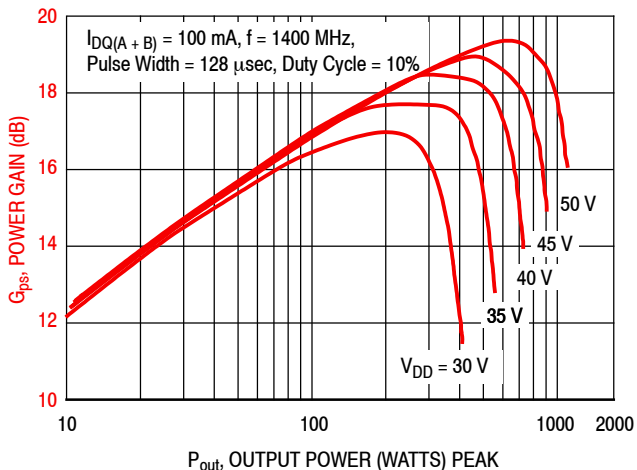


Figure 8. Power Gain versus Output Power

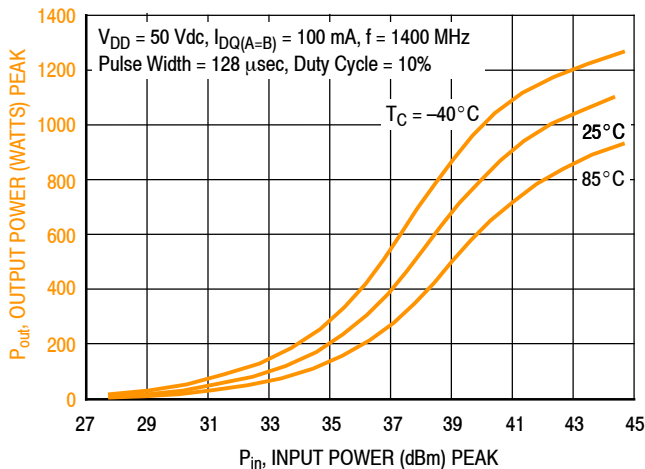


Figure 9. Output Power versus Input Power

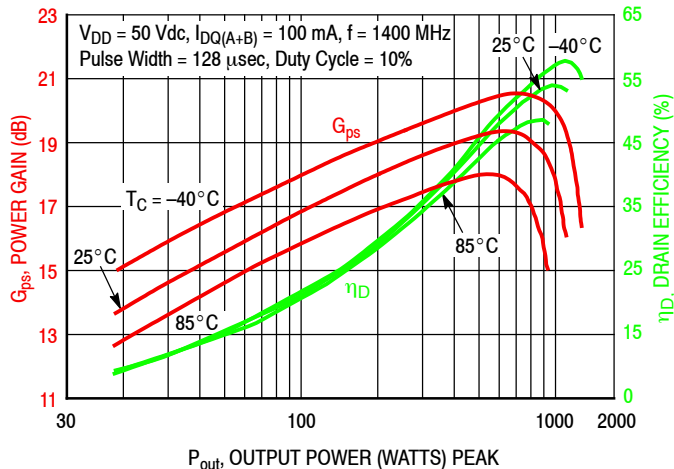


Figure 10. Power Gain and Drain Efficiency versus Output Power

1400 MHz NARROWBAND PRODUCTION TEST FIXTURE

| f MHz | Z_{source} Ω | Z_{load} Ω |
|----------|--------------------------|------------------------|
| 1400 | $7.35 - j4.62$ | $1.3 - j.072$ |

Z_{source} = Test circuit impedance as measured from gate to gate, balanced configuration.

Z_{load} = Test circuit impedance as measured from drain to drain, balanced configuration.

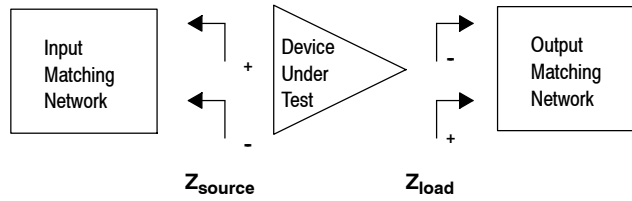
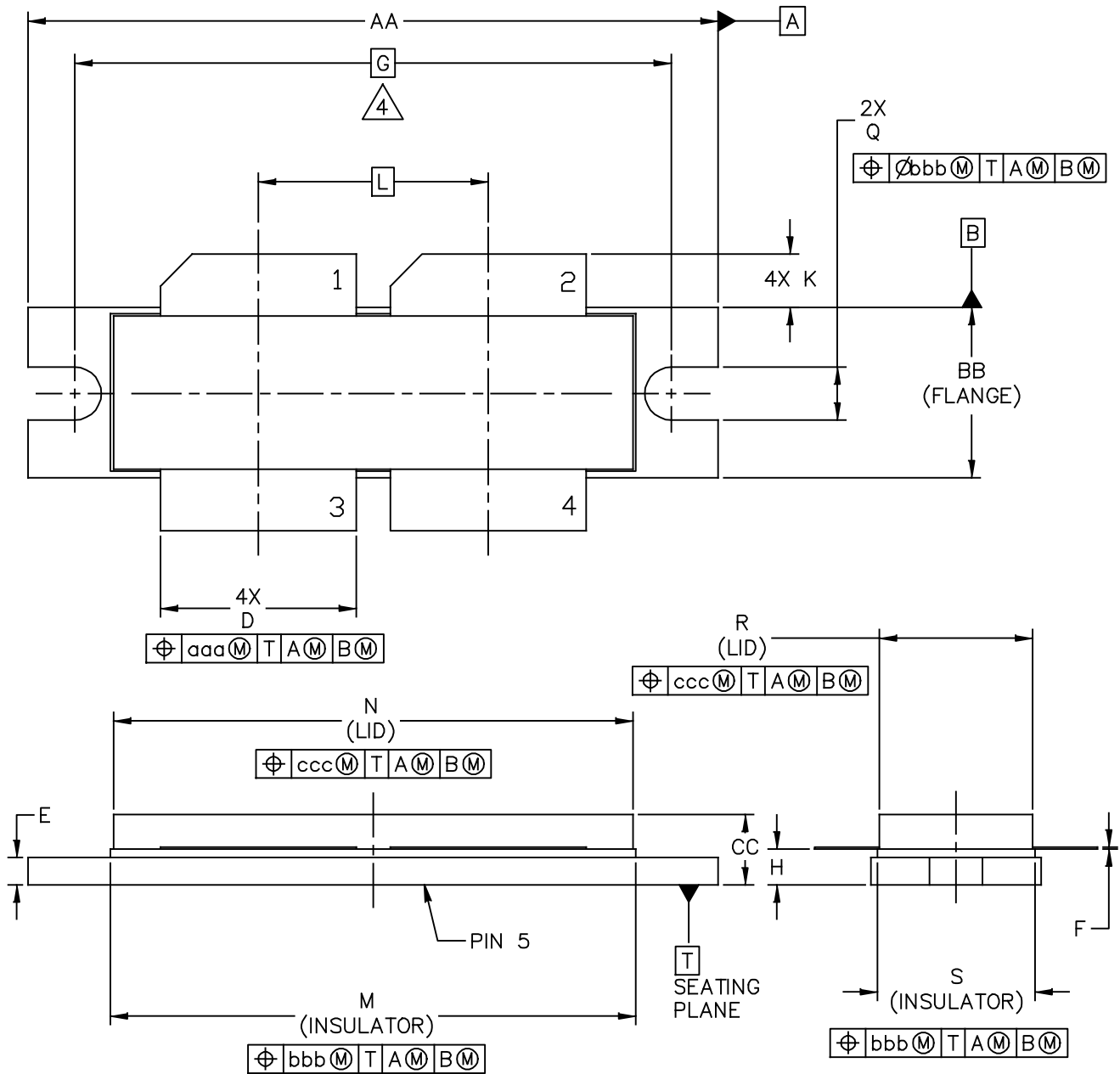


Figure 11. Narrowband Series Equivalent Source and Load Impedance — 1400 MHz

PACKAGE DIMENSIONS

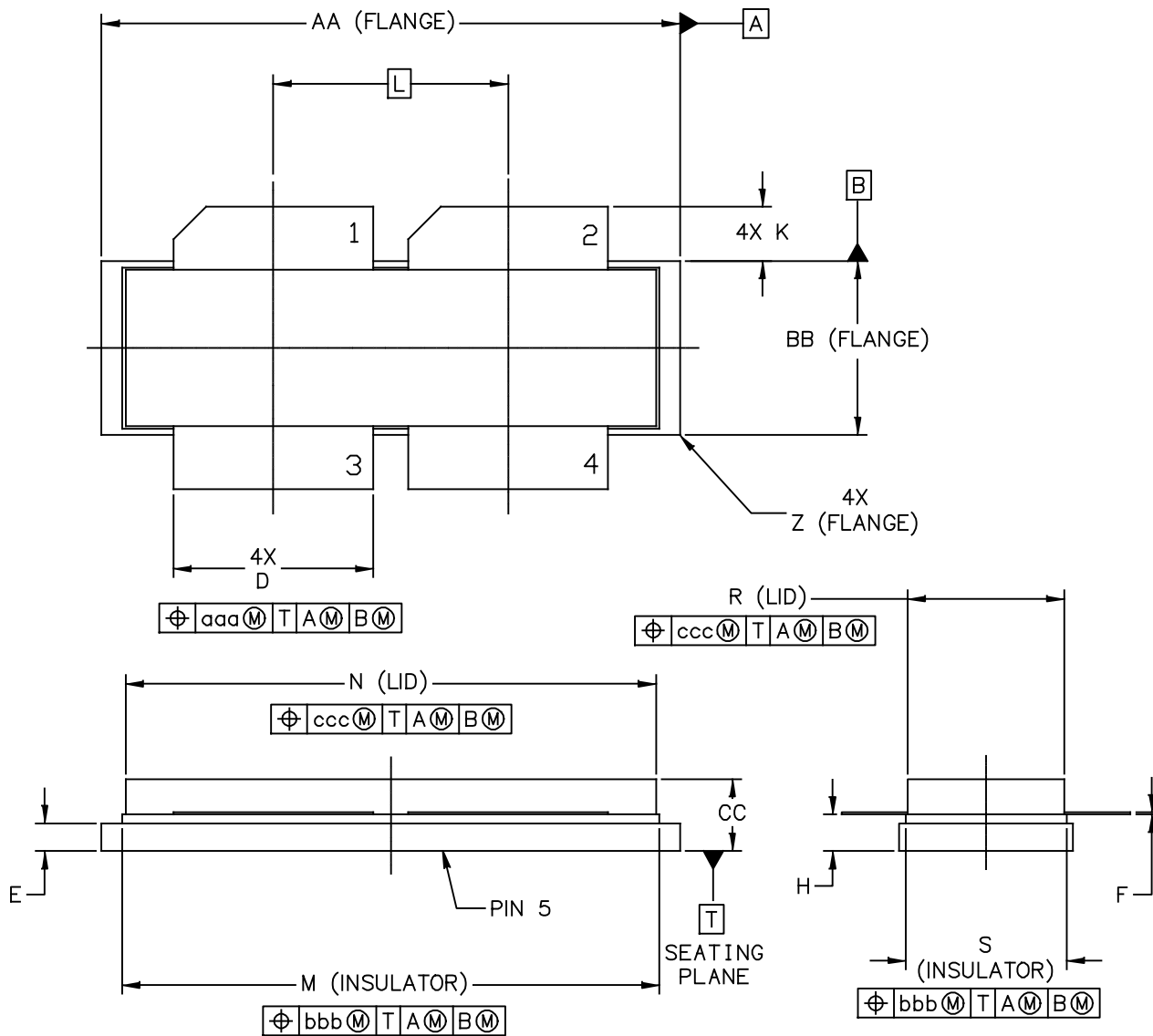


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| TITLE: NI-1230-4H | | DOCUMENT NO: 98ASB16977C REV: G STANDARD: NON-JEDEC SOT1787-1 03 MAR 2016 |

NOTES:

1. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M-1994.
2. CONTROLLING DIMENSION: INCH
3. DIMENSION H IS MEASURED .030 INCH (0.762 MM) AWAY FROM PACKAGE BODY.
4. RECOMMENDED BOLT CENTER DIMENSION OF 1.52 INCH (38.61 MM) BASED ON M3 SCREW.

| DIM | INCH | | MILLIMETER | | DIM | INCH | | MILLIMETER | |
|--|-----------|-------|--------------------|-------|--------------------------|----------------------------|-------------|------------|-------|
| | MIN | MAX | MIN | MAX | | MIN | MAX | MIN | MAX |
| AA | 1.615 | 1.625 | 41.02 | 41.28 | N | 1.218 | 1.242 | 30.94 | 31.55 |
| BB | .395 | .405 | 10.03 | 10.29 | Q | .120 | .130 | 3.05 | 3.30 |
| CC | .170 | .190 | 4.32 | 4.83 | R | .355 | .365 | 9.02 | 9.27 |
| D | .455 | .465 | 11.56 | 11.81 | S | .365 | .375 | 9.27 | 9.53 |
| E | .062 | .066 | 1.57 | 1.68 | | | | | |
| F | .004 | .007 | 0.10 | 0.18 | | | | | |
| G | 1.400 BSC | | 35.56 BSC | | aaa | .013 | | 0.33 | |
| H | .082 | .090 | 2.08 | 2.29 | bbb | .010 | | 0.25 | |
| K | .117 | .137 | 2.97 | 3.48 | ccc | .020 | | 0.51 | |
| L | .540 BSC | | 13.72 BSC | | | | | | |
| M | 1.219 | 1.241 | 30.96 | 31.52 | | | | | |
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| NI-1230-4H | | | | | STANDARD: NON-JEDEC | | | | |
| | | | | | SOT1787-1 | | 03 MAR 2016 | | |

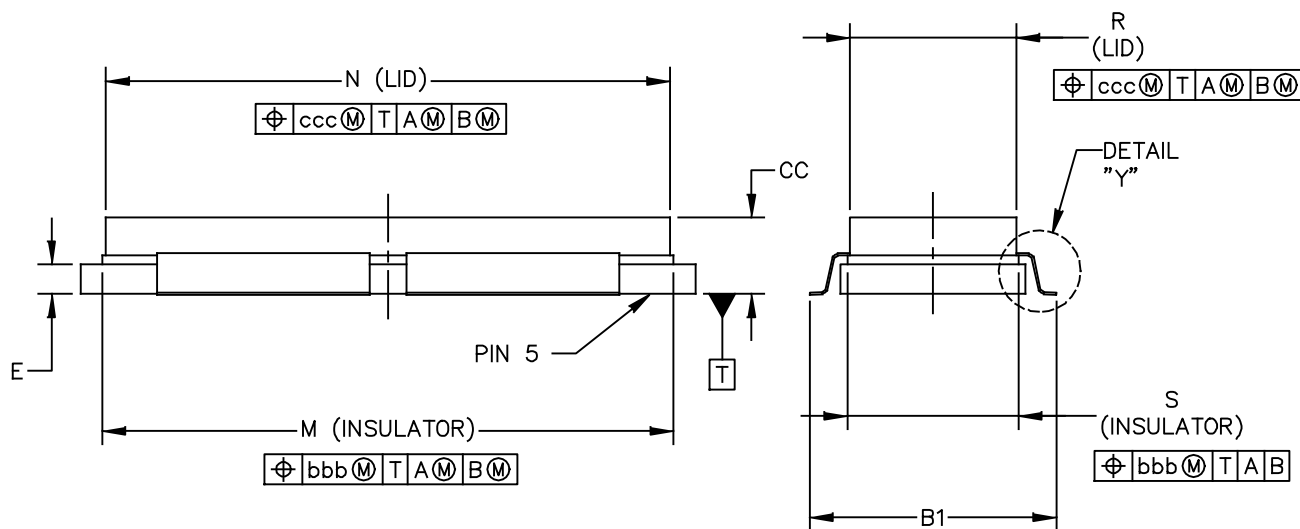
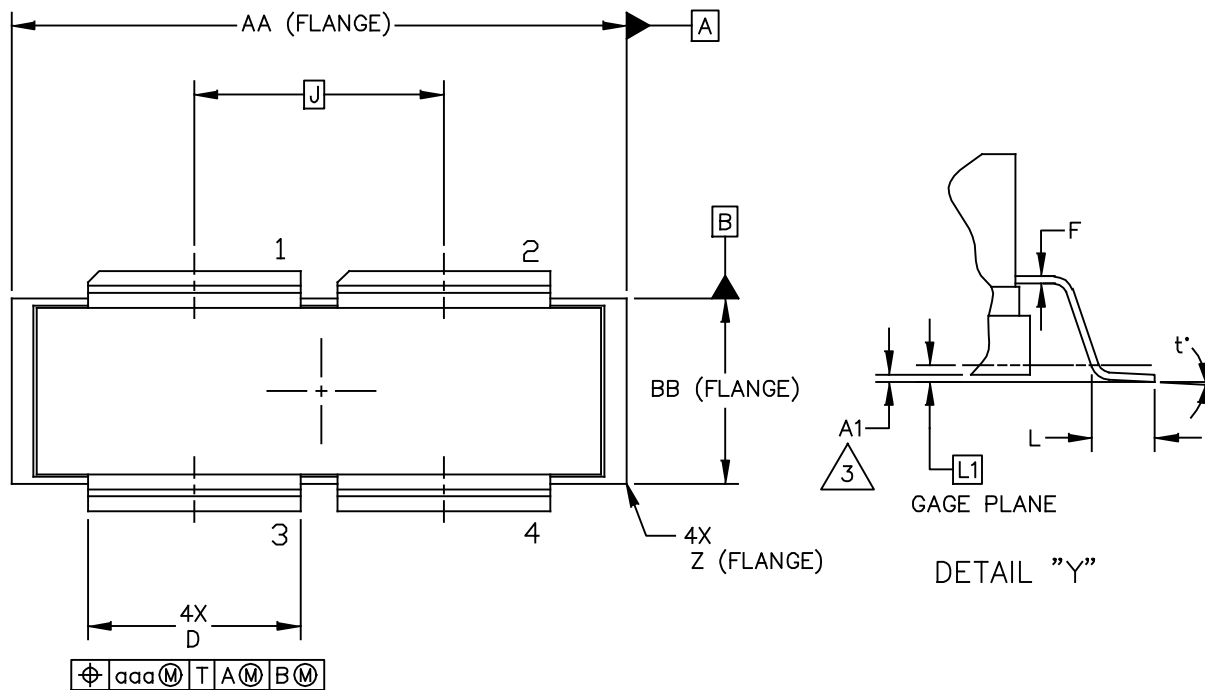


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| | STANDARD: NON-JEDEC | |
| | SOT1829-1 | 19 FEB 2016 |

NOTES:

1. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M-1994.
2. CONTROLLING DIMENSION: INCH
3. DIMENSION H IS MEASURED .030 INCH (0.762 MM) AWAY FROM PACKAGE BODY

| DIM | INCHES | | MILLIMETERS | | DIM | INCHES | | MILLIMETERS | |
|--|----------|-------|--------------------|-------|--------------------------------------|----------------------------|-------|-------------|-------|
| | MIN | MAX | MIN | MAX | | MIN | MAX | MIN | MAX |
| AA | 1.265 | 1.275 | 32.13 | 32.39 | R | .355 | .365 | 9.02 | 9.27 |
| BB | .395 | .405 | 10.03 | 10.29 | S | .365 | .375 | 9.27 | 9.53 |
| CC | .170 | .190 | 4.32 | 4.83 | Z | R.000 | R.040 | R0.00 | R1.02 |
| D | .455 | .465 | 11.56 | 11.81 | | | | | |
| E | .062 | .066 | 1.57 | 1.68 | aaa | .013 | | 0.33 | |
| F | .004 | .007 | 0.10 | 0.18 | bbb | .010 | | 0.25 | |
| H | .082 | .090 | 2.08 | 2.29 | ccc | .020 | | 0.51 | |
| K | .117 | .137 | 2.97 | 3.48 | | | | | |
| L | .540 BSC | | 13.72 BSC | | | | | | |
| M | 1.219 | 1.241 | 30.96 | 31.52 | | | | | |
| N | 1.218 | 1.242 | 30.94 | 31.55 | | | | | |
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| | STANDARD: NON-JEDEC | |
| | SOT1806-2 | 23 FEB 2016 |

NOTES:

1. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M-1994.
2. CONTROLLING DIMENSION: INCH

3. DIMENSION A1 IS MEASURED WITH REFERENCE TO DATUM T. THE POSITIVE VALUE IMPLIES THAT THE PACKAGE BOTTOM IS HIGHER THAN THE LEAD BOTTOM.

| DIM | INCHES | | MILLIMETERS | | DIM | INCHES | | MILLIMETERS | |
|--|----------|-------|--------------------|-------|--------------------------|----------------------------|-------------|-------------|-------|
| | MIN | MAX | MIN | MAX | | MIN | MAX | MIN | MAX |
| AA | 1.265 | 1.275 | 32.13 | 32.39 | R | .355 | .365 | 9.02 | 9.27 |
| A1 | -.001 | .011 | -0.03 | 0.28 | S | .365 | .375 | 9.27 | 9.53 |
| BB | .395 | .405 | 10.03 | 10.29 | Z | R.000 | R.040 | R0.00 | R1.02 |
| B1 | .564 | .574 | 14.32 | 14.58 | t* | 0* | 8* | 0* | 8* |
| CC | .170 | .190 | 4.32 | 4.83 | | | | | |
| D | .455 | .465 | 11.56 | 11.81 | aaa | .013 | | 0.33 | |
| E | .062 | .066 | 1.57 | 1.68 | bbb | .010 | | 0.25 | |
| F | .004 | .007 | 0.10 | 0.18 | ccc | .020 | | 0.51 | |
| J | .540 BSC | | 13.72 BSC | | | | | | |
| L | .038 | .046 | 0.97 | 1.17 | | | | | |
| L1 | .01 BSC | | 0.25 BSC | | | | | | |
| M | 1.219 | 1.241 | 30.96 | 31.52 | | | | | |
| N | 1.218 | 1.242 | 30.94 | 31.55 | | | | | |
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| TITLE: | | | | | DOCUMENT NO: 98ASA00459D | | REV: B | | |
| NI-1230-4S GULL | | | | | STANDARD: NON-JEDEC | | | | |
| | | | | | SOT1806-2 | | 23 FEB 2016 | | |

PRODUCT DOCUMENTATION, SOFTWARE AND TOOLS

Refer to the following resources to aid your design process.

Application Notes

- AN1908: Solder Reflow Attach Method for High Power RF Devices in Air Cavity Packages
- AN1955: Thermal Measurement Methodology of RF Power Amplifiers

Engineering Bulletins

- EB212: Using Data Sheet Impedances for RF LDMOS Devices

Software

- Electromigration MTTF Calculator
- RF High Power Model
- .s2p File

Development Tools

- Printed Circuit Boards

To Download Resources Specific to a Given Part Number:

1. Go to <http://www.nxp.com/RF>
2. Search by part number
3. Click part number link
4. Choose the desired resource from the drop down menu

REVISION HISTORY

The following table summarizes revisions to this document.

| | | |
|---|-----------|---------------------------------|
| 0 | Apr. 2016 | • Initial Release of Data Sheet |
|---|-----------|---------------------------------|

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В нашем ассортименте представлены ведущие мировые производители активных и пассивных электронных компонентов.

Нашей специализацией является поставка электронной компонентной базы двойного назначения, продукции таких производителей как XILINX, Intel (ex.ALTERA), Vicor, Microchip, Texas Instruments, Analog Devices, Mini-Circuits, Amphenol, Glenair.

Сотрудничество с глобальными дистрибьюторами электронных компонентов, предоставляет возможность заказывать и получать с международных складов практически любой перечень компонентов в оптимальные для Вас сроки.

На всех этапах разработки и производства наши партнеры могут получить квалифицированную поддержку опытных инженеров.

Система менеджмента качества компании отвечает требованиям в соответствии с ГОСТ Р ИСО 9001, ГОСТ РВ 0015-002 и ЭС РД 009

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